

## **DESCRIPTION**

The SSF2814E uses advanced trench technology to provide excellent  $R_{\rm DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V.

#### **GENERAL FEATURES**

V<sub>DS</sub> = 20V,I<sub>D</sub> = 7A

 $R_{DS(ON)}$  < 28m $\Omega$  @  $V_{GS}$ =2.5V

 $R_{DS(ON)} < 26m\Omega @ V_{GS} = 3.1V$ 

 $R_{DS(ON)} < 22m\Omega \ \overline{\textcircled{o}} \ V_{GS} = 4V$ 

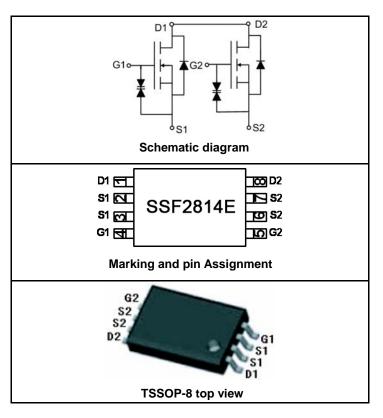
 $R_{DS(ON)} < 20 m\Omega @ V_{GS} = 4.5 V$ 

ESD Rating: 2000V HBM

- High Power and current handing capability
- Lead free product is acquired
- Surface Mount Package

## **Application**

- Battery protection
- Load switch
- Power management



### PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
SSF2814E	SSF2814E	TSSOP-8	Ø330mm	12mm	3000 units

ABSOLUTE MAXIMUM RATINGS(TA=25℃ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	20	V
Gate-Source Voltage	V <sub>G</sub> s	±12	V
Durin Coursest Continuous & Coursest Duland (Note 1)	I <sub>D</sub>	7	Α
Drain Current-Continuous@ Current-Pulsed (Note 1)	I <sub>DM</sub>	25	Α
Maximum Power Dissipation	P <sub>D</sub>	1.5	W
Operating Junction and Storage Temperature Range	$T_{J}, T_{STG}$	-55 To 150	$^{\circ}$ C

### THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Ambient (Note 2)	$R_{ heta JA}$	83	°C/W
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**ELECTRICAL CHARACTERISTICS (TA=25°C unless otherwise noted)** 

Parameter	Symbol	Condition	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250μA	20			V





Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =20V,V <sub>GS</sub> =0V			1	μA
Cata Bady Laglaga Current	I <sub>GSS</sub>	V <sub>GS</sub> =±4.5V,V <sub>DS</sub> =0V			±200	nA
Gate-Body Leakage Current		V <sub>GS</sub> =±10V,V <sub>DS</sub> =0V			±10	uA
ON CHARACTERISTICS (Note 3)						
Gate Threshold Voltage	$V_{GS(th)}$	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =250μA	0.6	0.75	1.2	V
	R <sub>DS(ON)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =6.5A		14	20	mΩ
Drain-Source On-State Resistance		V <sub>GS</sub> =4V, I <sub>D</sub> =6A		16	22	mΩ
Diain-Source On-State Resistance		V <sub>GS</sub> =3.1V, I <sub>D</sub> =5.5A		19	26	mΩ
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =5.5A		24	28	mΩ
Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> =10V,I <sub>D</sub> =6.5A		6.6		S
DYNAMIC CHARACTERISTICS (Note4)						
Input Capacitance	C <sub>lss</sub>			650		PF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> =8V,V <sub>GS</sub> =0V, F=1.0MHz		360		PF
Reverse Transfer Capacitance	C <sub>rss</sub>			154		PF
SWITCHING CHARACTERISTICS (Note 4)						
Turn-on Delay Time	t <sub>d(on)</sub>			11	22	nS
Turn-on Rise Time	t <sub>r</sub>	V <sub>DD</sub> =10V,I <sub>D</sub> =1A		12	28	nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =4.5V, $R_{GEN}$ =6 $\Omega$		35	73	nS
Turn-Off Fall Time	t <sub>f</sub>			33	65	nS
Total Gate Charge	$Q_g$			11	16	nC
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ =10V, $I_{D}$ =7A, $V_{GS}$ =4.5V		2.5		nC
Gate-Drain Charge	$Q_{gd}$	1 00		3.2		nC
DRAIN-SOURCE DIODE CHARACTERISTICS						
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =1.5A		0.84	1.2	V

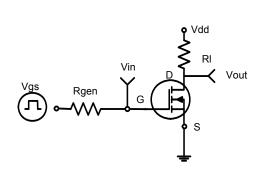
## **NOTES:**

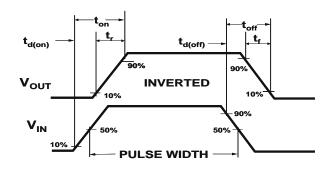
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.

- Surface Mounted on FR4 Board, t ≤ 10 sec.
  Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
  Guaranteed by design, not subject to production testing.



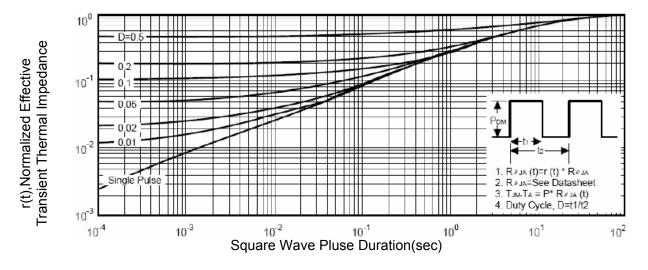
## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS





**Figure 1:Switching Test Circuit** 

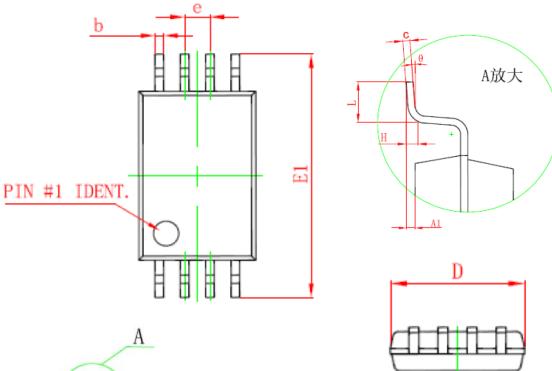
**Figure 2:Switching Waveforms** 

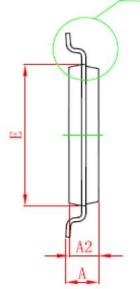


**Figure 3 Normalized Maximum Transient Thermal Impedance** 



# **TSSOP-8 PACKAGE INFORMATION**





Symbol	Dimension I	n Millimeters	Dimension In Inches		
Syllibol	Min	Max	Min	Max	
D	2.900	3.100	0.114	0.122	
Е	4.300	4.500	0.169	0.177	
b	0.190	0.300	0.007	0.012	
С	0.090	0.200	0.004	0.008	
E1	6.250	6.550	0.246	0.258	
Α		1.100		0.043	
A2	0.800	1.000	0.031	0.039	
A1	0.020	0.150	0.001	0.006	
е	0.65 (BSC)		0.026 (BSC)		
L	0.500	0.700	0.020	0.028	
Н	0.25 TYP		0.01 TYP		
θ	1 <sup>0</sup>	7 <sup>0</sup>	1 <sup>0</sup>	7 <sup>0</sup>	

## NOTES:

- Dimensions are inclusive of plating
  Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 6 mils.
- Dimension L is measured in gauge plane.
  Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.



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